

RELIABILITY REPORT FOR

USE THIS PART FOR DS1220Y

DS1220 Rev D2 AD

Dallas Semiconductor

4401 South Beltwood Parkway Dallas, TX 75244-3292

Prepared by:

Ken Windel

Ken Wendel Reliability Engineering Manager Dallas Semiconductor 4401 South Beltwood Pkwy. Dallas, TX 75244-3292

Email: ken.wendel@dalsemi.com

ph: 972-371-3726 fax: 972-371-6016 mbl: 214-435-6610

Conclusion:

The following qualification successfully meets the quality and reliability standards required of all Dallas Semiconductor products and processes:

In addition, Dallas Semiconductor's continuous reliability monitor program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards. The current status of the reliability monitor program can be viewed at http://www.maxim-ic.com/TechSupport/dsreliability.html.*

Module Description:

A description of this Module can be found in the product data sheet. You can find the product data sheet at http://dbserv.maxim-ic.com/l_datasheet3.cfm.*

Reliability Derating:

A module device consists of one or more IC's in a single, upward integrated, package. This package is assembled to include batteries, crystals, and other piece parts that make up the configuration of the Module. Because of either the complexity of the package or the included piece parts, standard high temperature reliability testing is not possible. Therefore, in order to determine the reliability of module products, the reliability of each of the piece parts is individually determined, then summed to determine the reliability of the integrated module product. If there are "n" significant components in the module then:

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Fr (module) = Fr (1) + Fr (2) + Fr (3) + ..... + Fr (n)
Fr (module) = Failure rate of module
Fr(n) = Failure rate of the nth component
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Failure Rates are reported in FITs (Failures in Time) or MTTF (Mean Time To Failure). The FIT rate is related to MTTF by:

MTTF = 1/Fr

NOTE: MTTF is frequently used interchangeably with MTBF.

The calculated failure rate for this module/assembly is:

Module Device:	Quantity:	MTTF (Yrs): FIT:	
DS7864	1	18096	6.3
BR1225	1	173708	0.7
Totals:		16388	7.0

The parameters used to calculate the module failure rate are as follows:

Cf: 60% Ea: 0.7 B: 0 Tu: 25 °C Vu: 5.5 Volts

The reliability data follows. A the start of this data is the module assembly information. This is a description of the module. The next section is the detailed reliability data for each stress found in the qualification / monitor. If there are additional processes or assemblies used as part of this report, a description of each will follow which includes the respective reliability data for that process/ assembly. The reliability data section includes the latest data available.

Assembly Information:

Assembly Site: Fastech Pin Count: 24

Package Type: Module w/Thru Hole

Body Size: 720 mil
Mold Compound: Amicon
Lead Frame: PCB; FR4

Die Attach:

Flammability: UL 94-V0

Date Code Range: 0311 to 0401

PACKAGE TESTS						
DESCRIPTION	DATE CODE	CONDITION	REA	DPOINT	QUANTITY	FAILS
SOLDERABILITY	0311	JESD22-B102	1	DYS	3	0
PHYSICAL DIMENSIONS	0311	JESD22-B100	1	DYS	6	0
SOLDERABILITY	0317	JESD22-B102	5	DYS	3	0
PHYSICAL DIMENSIONS	0317	JESD22-B100	5	DYS	6	0
SOLDERABILITY	0318	JESD22-B102	1	DYS	3	0
PHYSICAL DIMENSIONS	0318	JESD22-B100	1	DYS	6	0
SOLDERABILITY	0323	JESD22-B102	1	DYS	2	1
PHYSICAL DIMENSIONS	0323	JESD22-B100	1	DYS	6	0
SOLDERABILITY	0333	JESD22-B102	5	DYS	3	0
PHYSICAL DIMENSIONS	0333	JESD22-B100	5	DYS	6	0
SOLDERABILITY	0348	JESD22-B102	3	DYS	3	0
X-RAY	0348	MIL-STD-883-2012 : TOP & SIDE VIEW	3	DYS	3	0
PHYSICAL DIMENSIONS		JESD22-B100	3	DYS	3	0
MARK PERMANENCY		JESD22-B107	3	DYS	3	0
LEAD INTEGRITY		JESD22-B105 TEST CONDITION B	3	DYS	3	0
				Tota	al:	1

STORAGE LIFE						
DESCRIPTION	DATE CO	DE CONDITION	REA	DPOINT	QUANTITY	FAILS
STORAGE LIFE	0317	70 C	1000	HRS	77	0
STORAGE LIFE	0333	70 C	1000	HRS	77	0
STORAGE LIFE	0348	70 C	300	HRS	22	0

^{*} Some proprietary products may be excepted from this requirement.

STORAGE LIFE	0401	85 C	336 HRS 77 Total :	0 0
TEMPERATURE CYC	CLE			
DESCRIPTION	DATE CO	DE CONDITION	READPOINT QUANTITY	FAILS
TEMP CYCLE	0311	-40 TO 85C	300 CYS 100	0
TEMP CYCLE	0317	0C TO 70C	1000 CYS 77	0
TEMP CYCLE	0318	-40 TO 85C	300 CYS 100	0
TEMP CYCLE	0323	-40 TO 85C	300 CYS 100	0
TEMP CYCLE	0333	0C TO 70C	1000 CYS 77	0
TEMP CYCLE	0348	0C TO 70C	1000 CYS 22	O
TEMP CYCLE	0401	0C TO 70C	300 CYS 77	O
			Total:	0
TEMPERATURE HU	MIDITY BIAS	3		
DESCRIPTION	DATE CO	DE CONDITION	READPOINT QUANTITY	FAILS
BIASED MOISTURE	0311	85/85, 5.5 VOLTS	1000 HRS 100	0
BIASED MOISTURE	0318	85/85, 5.5 VOLTS	1000 HRS 100	0
BIASED MOISTURE	0323	85/85, 5.5 VOLTS	1000 HRS 100	0
			Total:	0
UNBIASED MOISTU	RE RESIST	ANCE		
DESCRIPTION	DATE CO	DE CONDITION	READPOINT QUANTITY	FAILS
MOISTURE SOAK	0317	60C/90% R.H.	1000 HRS 77	0
MOISTURE SOAK	0333	60C/90% R.H.	1000 HRS 77	0
MOISTURE SOAK	0348	60C/90% R.H.	300 HRS 22	O
MOISTURE SOAK	0401	60C/90% R.H.	336 HRS 77	0
			Total:	0